Abstracts

Temperature Noise Constants Extraction of mm-Wave FETs from Measured S- and Noise Parameters

A. Abdipour and A. Pacaud. "Temperature Noise Constants Extraction of mm-Wave FETs from Measured S- and Noise Parameters." 1996 MTT-S International Microwave Symposium Digest 96.3 (1996 Vol. III [MWSYM]): 1723-1726.

For the first time, the temperature noise constants of the full semidistributed FET model are extracted by a CAD-oriented method from measured S- and noise parameters, instead of curve fitting or by optimization procedure. Using extracted noise constants and their temperature variations, the temperature dependence of the noise parameters of the mm-wave FETs are here reported.

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